

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/065,365 BASSETT ET AL.	
		Examiner	Art Unit Cynthia Britt	Page 1 of 1 2133

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,448,796	09-2002	Ellison et al.	324/754
	B	US-6,658,613	12-2003	Rearick et al.	714/724
	C	US-6,556,938	04-2003	Rohrbaugh et al.	702/117
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	0388790	09-1990	EP	Littlebury	G01R/ 31/28
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"A Study of the Optimization of DC Parametric Tests" Chang, J.M. International Test Conference 1990 Proceedings: 10-14 Sept. 1990 pages 478 - 487 Inspec Accession Number: 3976214
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

